## P-Channel 1.5-V (G-S) MOSFET

| PRODUCT SUMMARY |  |  |  |
| :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\mathrm{DS}}(\mathrm{V})$ | $\mathrm{R}_{\mathrm{DS} \text { (on) }}(\Omega)$ | $\mathrm{I}_{\mathrm{D}}(\mathrm{A})^{\mathrm{e}}$ | $\mathrm{Q}_{\mathrm{g}}$ (Typ.) |
| - 8 | 0.036 at $\mathrm{V}_{\mathrm{GS}}=-4.5 \mathrm{~V}$ | -6 | 14 nC |
|  | 0.045 at $\mathrm{V}_{\mathrm{GS}}=-2.5 \mathrm{~V}$ | -6 |  |
|  | 0.056 at $\mathrm{V}_{\mathrm{GS}}=-1.8 \mathrm{~V}$ | -6 |  |
|  | 0.077 at $\mathrm{V}_{\mathrm{GS}}=-1.5 \mathrm{~V}$ | -6 |  |



Si5499DC-T1-GE3 (Lead (Pb)-free and Halogen-free)

## FEATURES

- Halogen-free According to IEC 61249-2-21 Available
- TrenchFET ${ }^{\circledR}$ Power MOSFET: 1.5 V Rated
- Ultra-Low On-Resistance


## APPLICATIONS

- Load Switch for Portable Devices
- Guaranteed Operation at $\mathrm{V}_{\mathrm{GS}}=1.5 \mathrm{~V}$ Critical for Optimized Design and Longer Battery Life


P-Channel MOSFET

| Parameter |  | Symbol | Limit | Unit |
| :---: | :---: | :---: | :---: | :---: |
| Drain-Source Voltage |  | $V_{\text {DS }}$ | -8 | V |
| Gate-Source Voltage |  | $\mathrm{V}_{\mathrm{GS}}$ | $\pm 5$ |  |
| Continuous Drain Current ( $\left.\mathrm{T}_{J}=150^{\circ} \mathrm{C}\right)^{\text {a, b }}$ | $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | $I_{\text {D }}$ | -6 ${ }^{\text {e }}$ | A |
|  | $\mathrm{T}_{\mathrm{C}}=70^{\circ} \mathrm{C}$ |  | $-6^{\text {e }}$ |  |
|  | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  | $-6^{\text {a,b, e }}$ |  |
|  | $\mathrm{T}_{\mathrm{A}}=70^{\circ} \mathrm{C}$ |  | $-5.6^{\text {a, b }}$ |  |
| Pulsed Drain Current (10 $\mu \mathrm{s}$ Pulse Width) |  | IDM | - 25 |  |
| Continuous Source-Drain Diode Current ${ }^{\text {a }}$, ${ }^{\text {b }}$ | $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | Is | -5.2 |  |
|  | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  | $-2.1{ }^{\text {a, b }}$ |  |
| Maximum Power Dissipation ${ }^{\text {a, b }}$ | $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | $P_{\text {D }}$ | 6.2 | W |
|  | $\mathrm{T}_{\mathrm{C}}=70^{\circ} \mathrm{C}$ |  | 4 |  |
|  | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ |  | $2.5{ }^{\text {a, b }}$ |  |
|  | $\mathrm{T}_{\text {A }}=70^{\circ} \mathrm{C}$ |  | $1.6{ }^{\text {a, b }}$ |  |
| Operating Junction and Storage Temperature Range |  | $\mathrm{T}_{\mathrm{J},} \mathrm{T}_{\text {stg }}$ | - 55 to 150 | ${ }^{\circ} \mathrm{C}$ |
| Soldering Recommendations (Peak Temperature) ${ }^{\text {c, } \mathrm{d}}$ |  |  | 260 |  |

## Notes:

a. Surface Mounted on 1" x 1" FR4 board.
b. $t=5 \mathrm{~s}$.
c. See Solder Profile (www.vishay.com/ppg?73257). The ChipFET is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
d. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.
e. Package limited.

| THERMAL RESISTANCE RATINGS |  |  |  |  |  |
| :--- | :---: | :---: | :---: | :---: | :---: |
| Parameter |  | Symbol | Typical | Maximum | Unit |
| Maximum Junction-to-Ambient ${ }^{\mathrm{a}, \mathrm{b}}$ | $\mathrm{t} \leq 5 \mathrm{~s}$ | $\mathrm{R}_{\mathrm{thJA}}$ | 48 | 50 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Maximum Junction-to-Foot (Drain) | Steady State | $\mathrm{R}_{\mathrm{th} \mathrm{hF}}$ | 17 | 20 |  |

## Notes:

a. Surface Mounted on 1" x 1" FR4 board.
b. Maximum under Steady State conditions is $95^{\circ} \mathrm{C} / \mathrm{W}$.

| SPECIFICATIONS $\mathrm{T}_{J}=25^{\circ} \mathrm{C}$, unless otherwise noted |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Parameter | Symbol | Test Conditions | Min. | Typ. | Max. | Unit |
| Static |  |  |  |  |  |  |
| Drain-Source Breakdown Voltage | $\mathrm{V}_{\mathrm{DS}}$ | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=-250 \mu \mathrm{~A}$ | -8 |  |  | V |
| $\mathrm{V}_{\text {DS }}$ Temperature Coefficient | $\Delta \mathrm{V}_{\mathrm{DS}} / \mathrm{T}_{\mathrm{J}}$ | $\mathrm{I}_{\mathrm{D}}=-250 \mu \mathrm{~A}$ |  | 6 |  | $\mathrm{mV} /{ }^{\circ} \mathrm{C}$ |
| $\mathrm{V}_{\mathrm{GS} \text { (th) }}$ Temperature Coefficient | $\Delta \mathrm{V}_{\mathrm{GS}(\mathrm{th})} / \mathrm{T}_{\mathrm{J}}$ |  |  | 2.3 |  |  |
| Gate-Source Threshold Voltage | $\mathrm{V}_{\mathrm{GS}(\text { (th) }}$ | $\mathrm{V}_{\mathrm{DS}}=\mathrm{V}_{\mathrm{GS}}, \mathrm{I}_{\mathrm{D}}=-250 \mu \mathrm{~A}$ | -0.35 |  | -0.8 | V |
|  |  | $\mathrm{V}_{\mathrm{DS}}=\mathrm{V}_{\mathrm{GS}}, \mathrm{I}_{\mathrm{D}}=-5 \mathrm{~mA}$ |  | -0.55 |  |  |
| Gate-Source Leakage | $\mathrm{I}_{\text {GSS }}$ | $\mathrm{V}_{\mathrm{DS}}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}= \pm 5 \mathrm{~V}$ |  |  | $\pm 100$ | nA |
| Zero Gate Voltage Drain Current | $\mathrm{I}_{\text {DSS }}$ | $\mathrm{V}_{\mathrm{DS}}=-8 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}$ |  |  | -1 | $\mu \mathrm{A}$ |
|  |  | $\mathrm{V}_{\mathrm{DS}}=-8 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{~T}_{J}=55^{\circ} \mathrm{C}$ |  |  | -10 |  |
| On-State Drain Current ${ }^{\text {a }}$ | $\mathrm{I}_{\mathrm{D} \text { (on) }}$ | $\mathrm{V}_{\mathrm{DS}} \leq 5 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=-4.5 \mathrm{~V}$ | -25 |  |  | A |
| Drain-Source On-State Resistance ${ }^{\text {a }}$ | $\mathrm{R}_{\mathrm{DS} \text { (on) }}$ | $\mathrm{V}_{\mathrm{GS}}=-4.5 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=-5.1 \mathrm{~A}$ |  | 0.030 | 0.036 | $\Omega$ |
|  |  | $\mathrm{V}_{\mathrm{GS}}=-2.5 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=-4.6 \mathrm{~A}$ |  | 0.037 | 0.045 |  |
|  |  | $\mathrm{V}_{\mathrm{GS}}=-1.8 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=-4.3 \mathrm{~A}$ |  | 0.046 | 0.056 |  |
|  |  | $\mathrm{V}_{\mathrm{GS}}=-1.5 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=-1.3 \mathrm{~A}$ |  | 0.057 | 0.077 |  |
| Forward Transconductance ${ }^{\text {a }}$ | $\mathrm{g}_{\mathrm{fs}}$ | $V_{D S}=-4 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=-5.1 \mathrm{~A}$ |  | 18 |  | S |
| Dynamic ${ }^{\text {b }}$ |  |  |  |  |  |  |
| Input Capacitance | $\mathrm{C}_{\text {iss }}$ | $\mathrm{V}_{\mathrm{DS}}=-4 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{f}=1 \mathrm{MHz}$ |  | 1290 |  | pF |
| Output Capacitance | $\mathrm{C}_{\text {oss }}$ |  |  | 420 |  |  |
| Reverse Transfer Capacitance | $\mathrm{C}_{\text {rss }}$ |  |  | 270 |  |  |
| Total Gate Charge | $Q_{g}$ | $\mathrm{V}_{\mathrm{DS}}=-4 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=-8 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=-6 \mathrm{~A}$ |  | 23 | 35 | nC |
|  |  | $\mathrm{V}_{\mathrm{DS}}=-4 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=-4.5 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=-6 \mathrm{~A}$ |  | 14 | 21 |  |
| Gate-Source Charge | $\mathrm{Q}_{\mathrm{gs}}$ |  |  | 1.7 |  |  |
| Gate-Drain Charge | $\mathrm{Q}_{\mathrm{gd}}$ |  |  | 2.7 |  |  |
| Gate Resistance | $\mathrm{R}_{\mathrm{g}}$ | $\mathrm{f}=1 \mathrm{MHz}$ |  | 8 |  | $\Omega$ |
| Turn-On Delay Time | $\mathrm{t}_{\mathrm{d}(\mathrm{on})}$ | $\begin{gathered} \mathrm{V}_{\mathrm{DD}}=-4 \mathrm{~V}, \mathrm{R}_{\mathrm{L}}=0.7 \Omega \\ \mathrm{I}_{\mathrm{D}} \cong-5.6 \mathrm{~A}, \mathrm{~V}_{\mathrm{GEN}}=-4.5 \mathrm{~V}, \mathrm{R}_{\mathrm{g}}=1 \Omega \end{gathered}$ |  | 10 | 15 | ns |
| Rise Time | $\mathrm{t}_{\mathrm{r}}$ |  |  | 70 | 110 |  |
| Turn-Off Delay Time | $\mathrm{t}_{\mathrm{d} \text { (off) }}$ |  |  | 60 | 90 |  |
| Fall Time | $\mathrm{t}_{\mathrm{f}}$ |  |  | 30 | 45 |  |
| Turn-On Delay Time | $\mathrm{t}_{\mathrm{d}(\mathrm{on})}$ | $\begin{gathered} \mathrm{V}_{\mathrm{DD}}=-4 \mathrm{~V}, \mathrm{R}_{\mathrm{L}}=0.7 \Omega \\ \mathrm{I}_{\mathrm{D}} \cong-5.6 \mathrm{~A}, \mathrm{~V}_{\mathrm{GEN}}=-8 \mathrm{~V}, \mathrm{R}_{\mathrm{g}}=1 \Omega \end{gathered}$ |  | 8 | 15 |  |
| Rise Time | $\mathrm{t}_{\mathrm{r}}$ |  |  | 70 | 110 |  |
| Turn-Off Delay Time | $t_{\text {d(off) }}$ |  |  | 55 | 85 |  |
| Fall Time | $\mathrm{t}_{\mathrm{f}}$ |  |  | 55 | 85 |  |


| SPECIFICATIONS $\mathrm{T}_{J}=25^{\circ} \mathrm{C}$, unless otherwise noted |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Parameter | Symbol | Test Conditions | Min. | Typ. | Max. | Unit |
| Drain-Source Body Diode Characteristics |  |  |  |  |  |  |
| Continuous Source-Drain Diode Current | Is | $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ |  |  | -6 |  |
| Pulse Diode Forward Current | $\mathrm{I}_{\text {SM }}$ |  |  |  | -25 | A |
| Body Diode Voltage | $\mathrm{V}_{\text {SD }}$ | $\mathrm{I}_{\mathrm{S}}=-2.1 \mathrm{~A}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}$ |  | -0.7 | -1.2 | V |
| Body Diode Reverse Recovery Time | $\mathrm{t}_{\mathrm{rr}}$ | $\mathrm{I}_{\mathrm{F}}=-5.6 \mathrm{~A}, \mathrm{dl} / \mathrm{dt}=100 \mathrm{~A} / \mu \mathrm{s}, \mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C}$ |  | 45 | 70 | ns |
| Body Diode Reverse Recovery Charge | $\mathrm{Q}_{\mathrm{rr}}$ |  |  | 18 | 27 | nC |
| Reverse Recovery Fall Time | $\mathrm{t}_{\mathrm{a}}$ |  |  | 18 |  | ns |
| Reverse Recovery Rise Time | $\mathrm{t}_{\mathrm{b}}$ |  |  | 17 |  | ns |

Notes:
a. Pulse test; pulse width $\leq 300 \mu \mathrm{~s}$, duty cycle $\leq 2 \%$.
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

TYPICAL CHARACTERISTICS $25^{\circ} \mathrm{C}$, unless otherwise noted



On-Resistance vs. Drain Current and Gate Voltage





On-Resistance vs. Junction Temperature

Si5499DC
Vishay Siliconix
TYPICAL CHARACTERISTICS $25^{\circ} \mathrm{C}$, unless otherwise noted


TYPICAL CHARACTERISTICS $25^{\circ} \mathrm{C}$, unless otherwise noted


[^0]Si5499DC
Vishay Siliconix
TYPICAL CHARACTERISTICS $25^{\circ} \mathrm{C}$, unless otherwise noted


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[^0]:    * The power dissipation $P_{D}$ is based on $T_{J(\max )}=150^{\circ} \mathrm{C}$, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

